

Lonten N-channel 650V, 7.2A, 0.65Ω LonFET™ Power MOSFET

Description

LonFET™ Power MOSFET is fabricated using **advanced super junction** technology. The resulting device has extremely low on resistance, making it especially suitable for applications which require superior power density and outstanding efficiency.

Features

- Ultra low $R_{DS(on)}$
- Ultra low gate charge (typ. $Q_g=14nC$)
- 100% UIS tested
- RoHS compliant

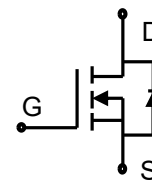
Applications

- Power factor correction (PFC).
- Switched mode power supplies (SMPS).
- Uninterruptible power supply (UPS).

Product Summary

V_{DS}	650V
$R_{DS(on), max}$	0.65Ω
I_{DM}	21.6A
$Q_{g,typ}$	14nC

Pin Configuration



N-Channel MOSFET



Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-Source Voltage	V_{DSS}	650	V
Continuous drain current ¹⁾ ($T_C = 25^\circ C$) ($T_C = 100^\circ C$)	I_D	7.2 4.5	A A
Pulsed drain current ²⁾	I_{DM}	21.6	A
Gate-Source voltage	V_{GSS}	± 30	V
Avalanche energy, single pulse ³⁾	E_{AS}	158.7	mJ
Power Dissipation	P_D	80	W
Operating and Storage Temperature Range	T_J, T_{STG}	-55 to +150	$^\circ C$
Continuous diode forward current	I_S	7.2	A
Diode pulse current	$I_{S,pulse}$	21.6	A

Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	1.56	$^\circ C/W$
Thermal Resistance, Junction-to-Ambient, minimal Footprint ⁴⁾	$R_{\theta JA}$	62	$^\circ C/W$
Soldering temperature, wave soldering only allowed at leads. (1.6mm from case for 10s)	T_{sold}	260	$^\circ C$

Package Marking and Ordering Information

Device	Device Package	Marking	Units/Reel
LSG65R650GMB	TO-252	LSG65R650GMB	2500

Electrical Characteristics

 $T_c = 25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Static characteristics						
Drain-source breakdown voltage	BV _{DSS}	V _{GS} =0V, I _D =250uA	650	-	-	V
Gate threshold voltage	V _{GS(th)}	V _{DS} =V _{GS} , I _D =250uA	2.5	3.5	4.5	V
Drain cut-off current	I _{DSS}	V _{DS} =650V, V _{GS} =0 V, T _J =25°C	-	-	1	μA
Gate leakage current, Forward	I _{GSSF}	V _{GS} =30V, V _{DS} =0 V	-	-	100	nA
Gate leakage current, Reverse	I _{GSSR}	V _{GS} =-30V, V _{DS} =0 V	-	-	-100	nA
Drain-source on-state resistance	R _{DS(on)}	V _{GS} =10V, I _D =3.5A T _J = 25°C T _J = 150°C	- - -	 0.57 1.378	 0.65 -	 Ω
Gate resistance	R _G	f=1 MHz, open drain	-	6.03	-	Ω
Dynamic characteristics						
Input capacitance	C _{iss}	V _{DS} =100V, V _{GS} =0V, f=250kHz	-	565	-	pF
Output capacitance	C _{oss}		-	21.55	-	
Reverse transfer capacitance	C _{rss}		-	0.77	-	
Turn-on delay time	t _{d(on)}	V _{DD} =400V, I _D =3.5A R _G = 10Ω, V _{GS} =10V	-	36.8	-	ns
Rise time	t _r		-	9.8	-	
Turn-off delay time	t _{d(off)}		-	27.9	-	
Fall time	t _f		-	15.6	-	
Gate charge characteristics						
Gate to source charge	Q _{gs}	V _{DD} =520V, I _D =3.5A, V _{GS} =0 to 10 V	-	2.9	-	nC
Gate to drain charge	Q _{gd}		-	6.3	-	
Gate charge total	Q _g		-	14	-	
Gate plateau voltage	V _{plateau}		-	5	-	V
Reverse diode characteristics						
Diode forward voltage	V _{SD}	V _{GS} =0 V, I _F =3.5A	-	-	1.1	V
Reverse recovery time	t _{rr}	V _R =400V, I _F =3.5A, dI _F /dt=100 A/μs	-	198.1	-	ns
Reverse recovery charge	Q _{rr}		-	1123.7	-	nC
Peak reverse recovery current	I _{rrm}		-	12.74	-	A

Notes:

- Limited by maximum junction temperature and duty cycle.
- Limited by maximum junction temperature, maximum duty cycle is 0.75.
- $I_{AS}=2.3A, L=60\text{mH}, V_{DD}=60V$, Starting $T_J=25^\circ\text{C}$.
- The value of R_{thJA} is measured by placing the device in a still air box which is one cubic foot.

Electrical Characteristics Diagrams

Fig 1: Output Characteristics

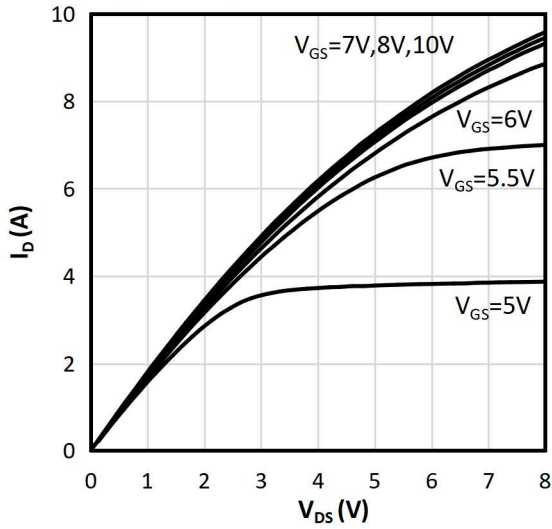


Fig 2: Transfer Characteristics

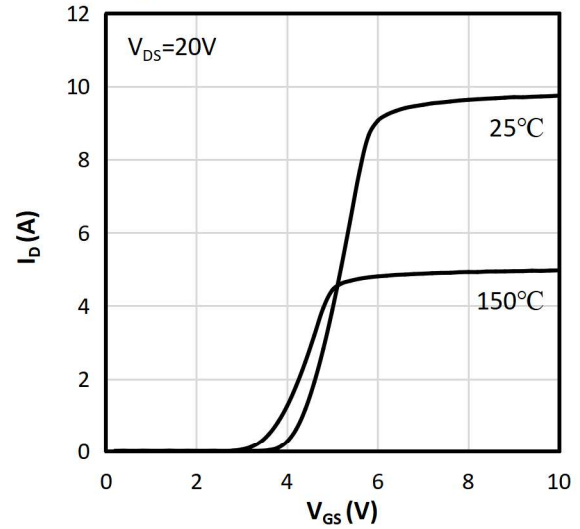


Fig 3: $R_{DS(on)}$ vs Drain Current

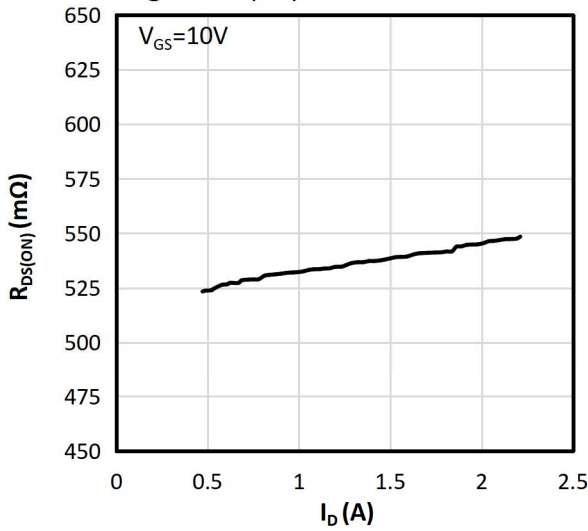


Fig 4: $R_{DS(on)}$ vs. Temperature

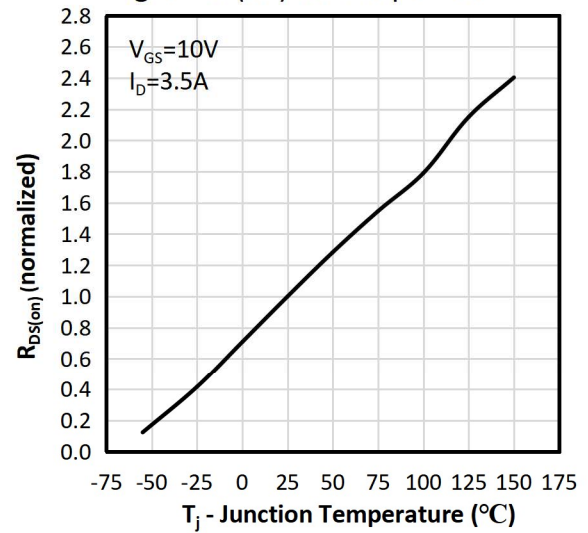


Fig 5: Breakdown Voltage vs. Temperature

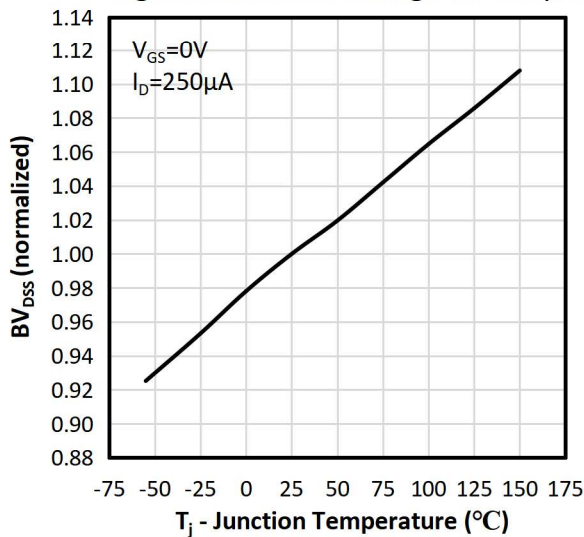


Fig 6: Threshold voltage vs. Temperature

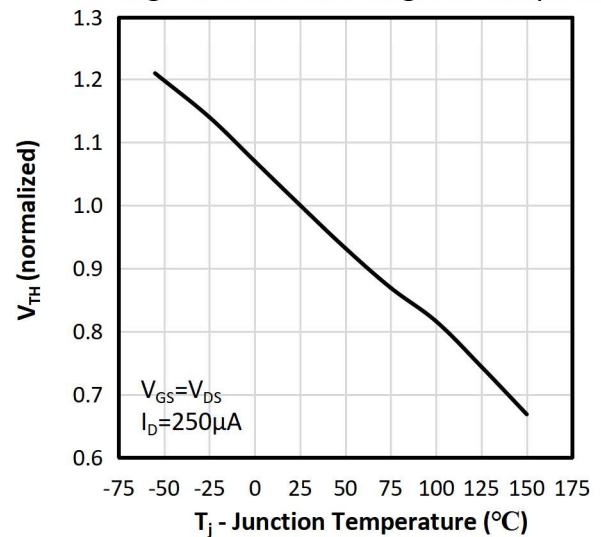


Fig 7: Body-Diode Characteristics

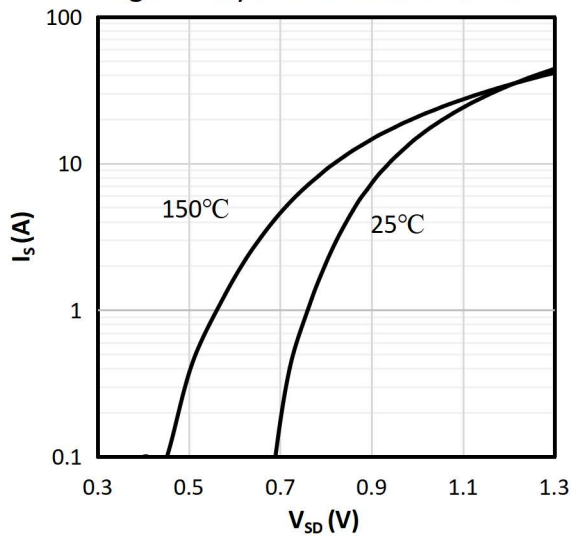


Fig 8: Capacitance Characteristics

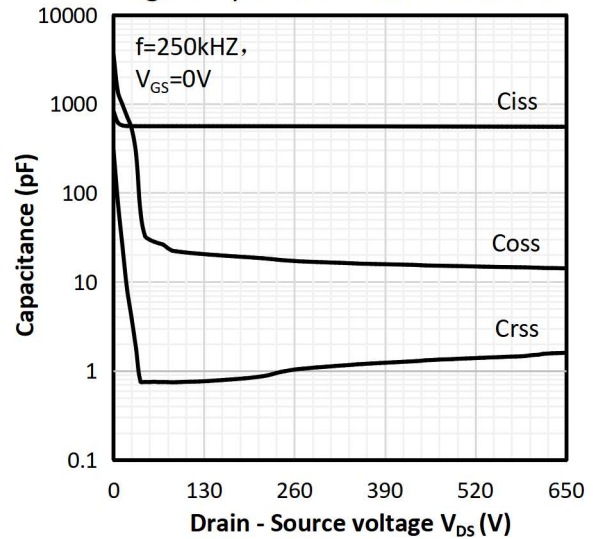


Fig 9: Gate charger Characteristics

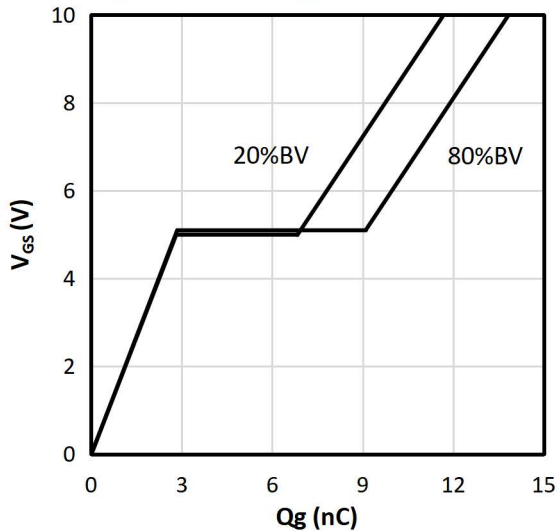


Fig 10: Drain Current Derating

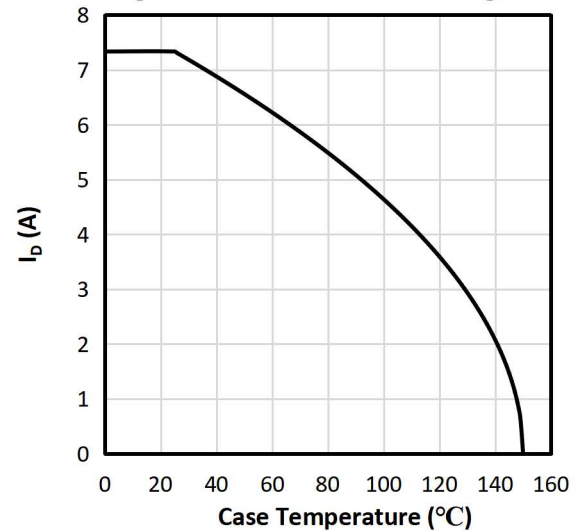


Fig 11: Power Dissipation vs. Temperature

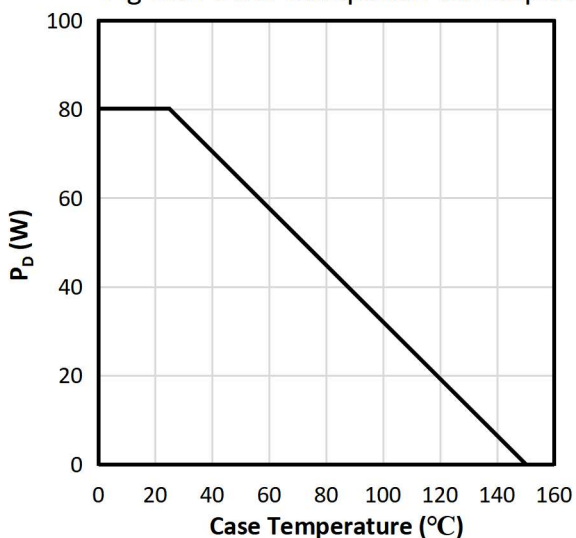


Fig 12: Safe Operating Area

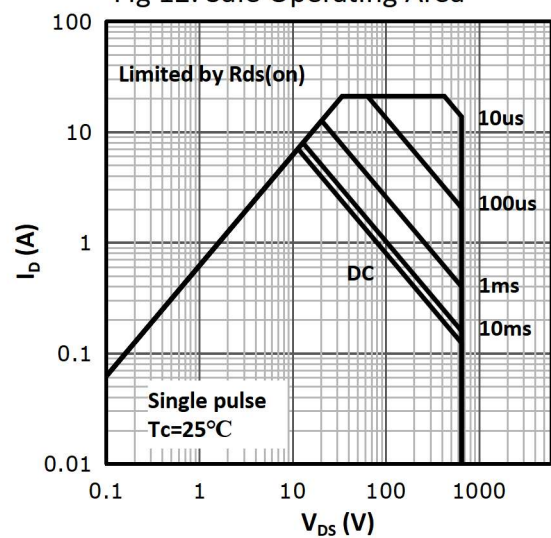
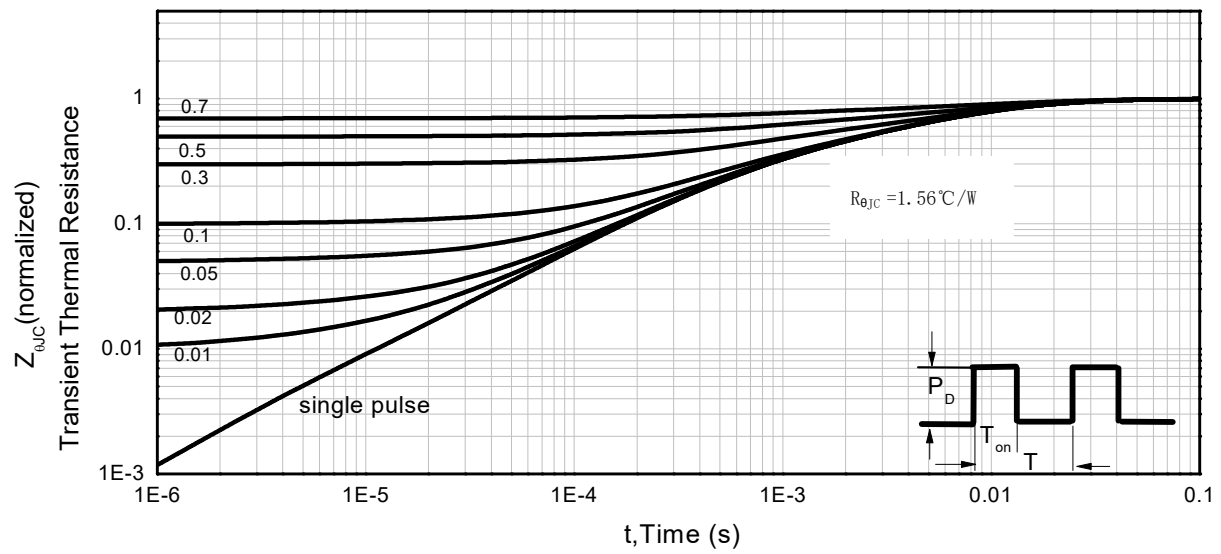
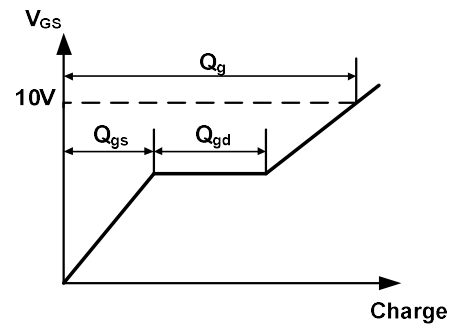
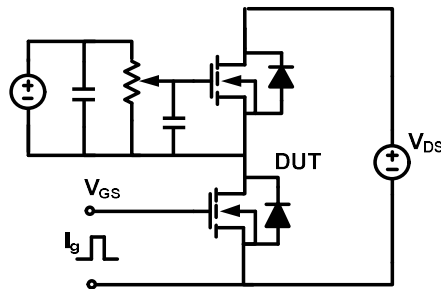


Figure 13. Normalized Maximum Transient Thermal Impedance (R_{thJC})

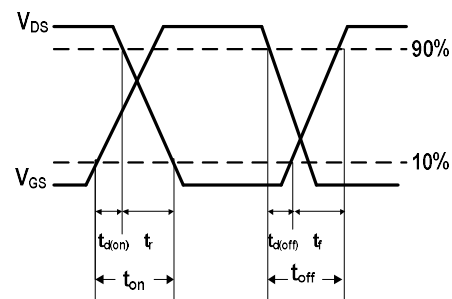
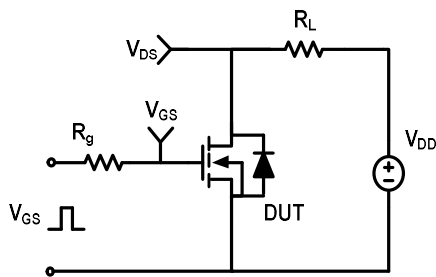


Test Circuit & Waveforms

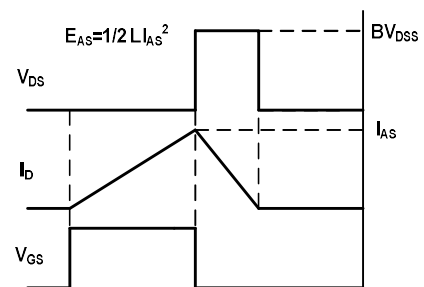
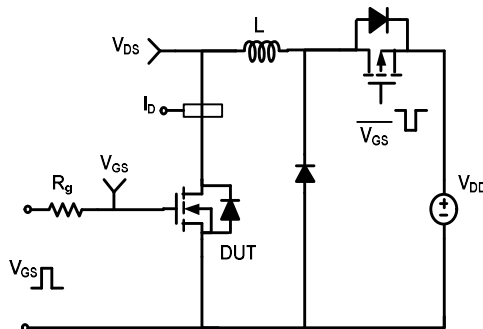
Gate Charge Test Circuit & Waveform



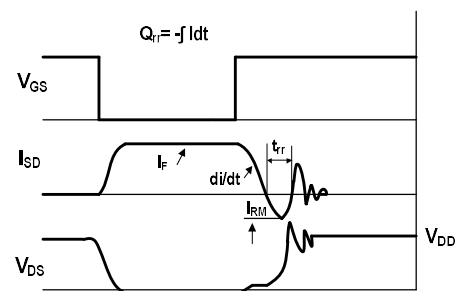
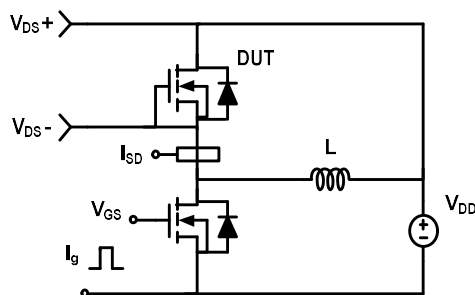
Resistive Switching Test Circuit & Waveform



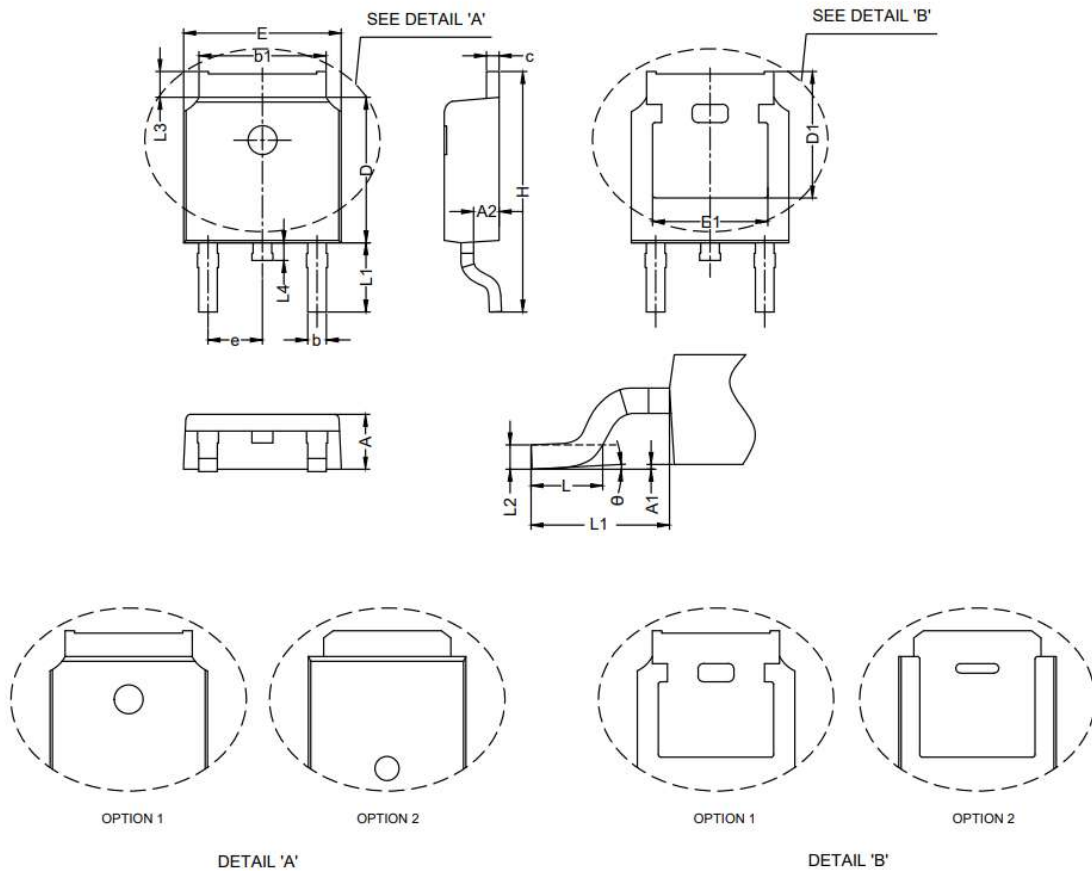
Unclamped Inductive Switching (UIS) Test Circuit & Waveform



Diode Recovery Test Circuit & Waveform



Mechanical Dimensions for TO-252



SYMBOLS	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.10	2.50	0.083	0.098
A1	0.00	0.20	0.000	0.008
A2	0.85	1.17	0.033	0.046
b	0.60	0.90	0.024	0.035
b1	4.95	5.48	0.195	0.216
c	0.41	0.61	0.016	0.024
D	5.95	6.35	0.234	0.250
D1	5.21	–	0.205	–
E	6.35	6.80	0.250	0.268
E1	4.32	–	0.170	–
e	2.286 BSC		0.090 BSC	
H	9.40	10.50	0.370	0.413
L	0.95	1.78	0.037	0.070
L1	2.90 REF		0.114 REF	
L2	0.51 BSC		0.020 BSC	
L3	0.88	1.28	0.035	0.050
L4	–	1.02	–	0.040
θ	0°	10°	0°	10°

Version Information

LSG65R650GMB

Revision 1.1

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